

Abstracts

Picosecond Photoconductive Switches Designed for On-Wafer Characterization of High Frequency Interconnects

L.P. Golob, S.L. Huang, C.H. Lee, W.H. Chang, K. Jones, M. Taysing-Lara and T. DeAnni.

"Picosecond Photoconductive Switches Designed for On-Wafer Characterization of High Frequency Interconnects." 1993 MTT-S International Microwave Symposium Digest 93.3 (1993 Vol. III [MWSYM]): 1395-1398.

Photoconductive switches fabricated by compatible microwave device processing techniques are used for on-wafer characterization of a long high-frequency interconnect, exceeding 160-GHz measurement bandwidth. Full characterization of this interconnect structure is important for determining cycle time of the future high speed computer.

[Return to main document.](#)